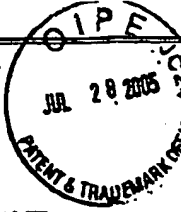


Form PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICELIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)ATTY. DOCKET NO.
MI22-1897SERIAL NO.
10/050,347APPLICANT
Gurtej S. SandhuFILING DATE
January 15, 2002GROUP
2813

U.S. PATENT DOCUMENTS

Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
<i>RL</i>	AA	3,627,598	12/71	McDonald et al.	—	—	
	AB	4,254,161	03/81	Kemlage	—	—	
	AC	4,262,631	04/81	Kubacki	—	—	
	AD	4,435,447	03/84	Ito et al.	—	—	
	AE	4,882,649	11/89	Chen et al.	—	—	
	AF	4,891,684	01/90	Nishioka et al.	—	—	
	AG	4,980,307	12/90	Ito et al.	—	—	
	AH	4,996,081	02/91	Ellul et al.	—	—	
	AJ	5,051,794	09/91	Mori	—	—	
<i>RL</i>	AJ	5,142,438	08/92	Reinberg et al.	—	—	

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
<i>RL</i>	AK	EP 0886308 A2	12/98	EPO	—	—		
<i>RL</i>	AL	237243 a	04/01	Japan	—	—		
	AM							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

<i>RL</i>	AN	Wolf, Stanley, <i>Silicon Processing for the VLSI Era</i> (1995), V.3, 648-9
<i>RL</i>	AO	Laughery et al., <i>Effect of H₂ Content on Reliability of Ultrathin In-Situ Steam Generated (ISSG) SiO₂</i> , Sept., 2000, Vol. 21, No. 9.
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Form PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				ATTY. DOCKET NO. M122-1898		SERIAL NO. 10/050,348	
				APPLICANT Gurtej S. Sandhu			
				FILING DATE January 15, 2002		GROUP 2813	

U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	5,227,651	07/93	Kim et al.		
	AB	5,237,188	08/93	Iwai et al.		
	AC	5,324,679	06/94	Kim et al.		
	AD	5,330,936	07/94	Ishitani		
	AE	5,350,707	09/94	Ko et al.		
	AF	5,376,593	12/94	Sandhu et al.		
	AG	5,393,702	02/95	Yang et al.		
	AH	5,397,748	03/95	Watanabe et al.		
	AI	5,398,641	03/95	Shih		
	AJ	5,459,105	10/95	Matsuura		

FOREIGN PATENT DOCUMENTS











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

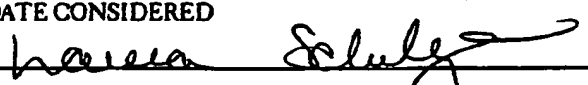
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

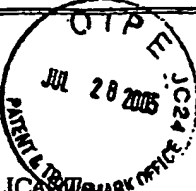




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U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Gurtej S. Sandhu				
				FILING DATE January 15, 2002		GROUP 2813		
U.S. PATENT DOCUMENTS								
Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
       	AA	5,498,890	03/96	Kim et al.				
	AB	5,504,029	04/96	Murata et al.				
	AC	5,508,542	04/96	Geiss et al.				
	AD	5,523,596	06/96	Ohi et al.				
	AE	5,731,235	03/98	Srinivasan et al.				
	AF	5,821,142	10/98	Sung et al.				
	AG	5,844,771	12/98	Graettinger et al.				
	AH	5,851,603	12/98	Tsai et al.				
	AI	5,882,978	03/99	Srinivasan et al.				
	AJ	6,001,741	12/99	Alers				
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
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U.S. PATENT DOCUMENTS								
Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
	AA	6,001,748	12/99	Tanaka				
	AB	6,008,104	12/99	Schrems				
	AC	6,051,865	04/00	Gardner et al.				
	AD	6,063,713	06/00	Doan				
	AE	6,077,754	06/00	Srinivasan et al.				
	AF	6,096,597	08/00	Tsu et al.				
	AG	6,111,744	08/00	Doan				
	AH	6,168,980	01/01	Yamazaki et al.				
	AI	6,207,985 B1	03/01	Walker				
		AJ	6,323,138 B1	11/01	Doan			
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U.S. PATENT DOCUMENTS									
Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate		
  	AA	6,348,420 B1	02/02	Raaijmakers et al.					
	AB	6,265,327	07/01	Kobayashi et al.					
	AC	6,350,707 B1	02/02	Liu et al.					
	AD	6,723,599 B2	04/04	Eppich et al.					
	AE	6,893,981 B2	05/05	Park et al.					
	AF	09/653,281	08/00	Beaman et al.					
	AG	2001/0036752	11/01	DeBoer et al.					
	AH	2002/0009861	08/98	Narvankar et al.					
	AI	2002/0052124	05/02	Raaijmakers et al.					
	AJ	2003/0034518A1	02/03	Yoshikawa					
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)									
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EXAMINER		DATE CONSIDERED  12/2/05							
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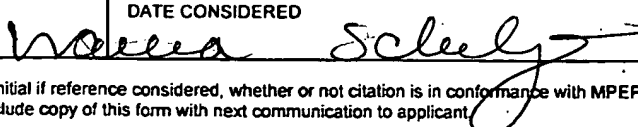
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U.S. PATENT DOCUMENTS							
Examiner's Initials	Class	Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
RL	AA	6,015,739	1/18/00	Gardner et al.			
RL	AB	6,057,854	05/2/00	Gardner et al.			
not considered		6,649,58 B1	11/18/03	Cheng et al.			
RL	AD	2005/0087820 A1	4/28/05	Bai et al.			
RL	AE	2006/0134864 A1	6/22/06	Higashitani et al.			
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FOREIGN PATENT DOCUMENTS								
Examiner's Initials	Class	Document Number	Date	Country	Class	Subclass	Translation	
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